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Sanghun Jeon is a tenured Full Professor in the School of Electrical Engineering at the Korea Advanced Institute of Science and Technology (KAIST) in Daejeon, South Korea. From 2003 to 2013, he worked at Samsung Electronics' R&D Center and the Samsung Advanced Institute of Technology, where he received multiple research awards. He later joined Korea University in Seoul as an Associate Professor. In 2018, he founded the ANTONIS Laboratory at KAIST.

During his sabbatical from 2022 to 2023, he worked as a technical advisory professor at Samsung Electronics Semiconductor Research Center, where he contributed to research on hafnia-based ferroelectric NAND flash and future technologies. His current research focuses on hafnia-based ferroelectric devices, including transistor, DRAM, NAND flash, processing-in-memory and in-sensor computing. This year, his research group made a significant international impact by presenting two papers at the VLSI Symposium in Hawaii and three at IEDM in San Francisco, showcasing leadership in ferroelectric and memory device advancements. Over the past four years, his team has published around 100 scientific and technical publication.

He also serves as the Managing Editor of Springer Nanoconvergence and is a Senior Member of IEEE.